Interagency Monitoring of Protected Visual Environments



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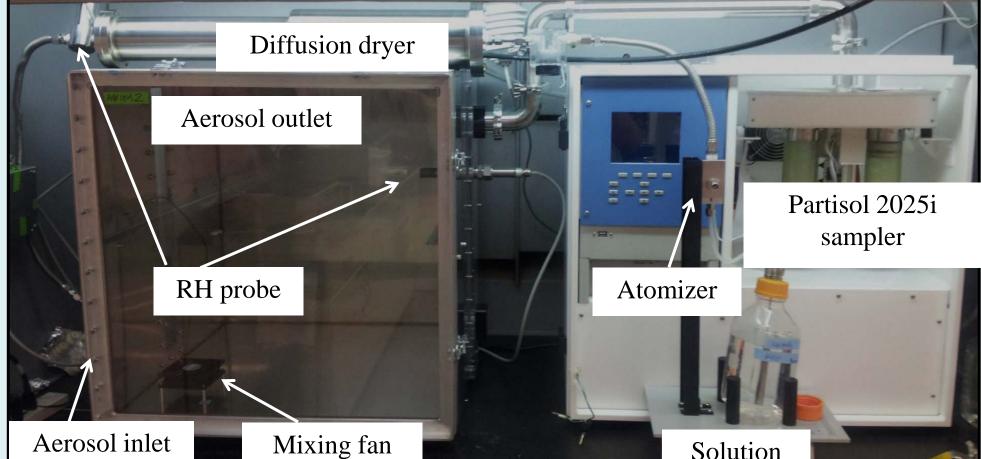
Objective: To generate single and multi-element reference materials (RMs) on Polytetrafluoroethylene (PTFE, Teflon) filters using aerosol chamber at CNL-UC Davis (Fig.1), and utilize them in calibration and quality control (QC) of EDXRF analyzers in order to address the limitations of available resources.

Materials & Method: High purity salts and nanoparticles for single compound RMs (SE-RMs) Certified multi-elemental solutions containing 28 elements for multi-element RMs (ME-RMs).

Certified or Reference loadings of RMs:

- The loadings of SE-RMs (C_{cer}) are certified gravimetrically using a balance with 0.1 µg sensitivity
- > The ME-RMs reference loading of element i (C_{ref.i}) was assigned assuming :
 - 1. The elemental ratios in solutions are preserved onto ME-RMs





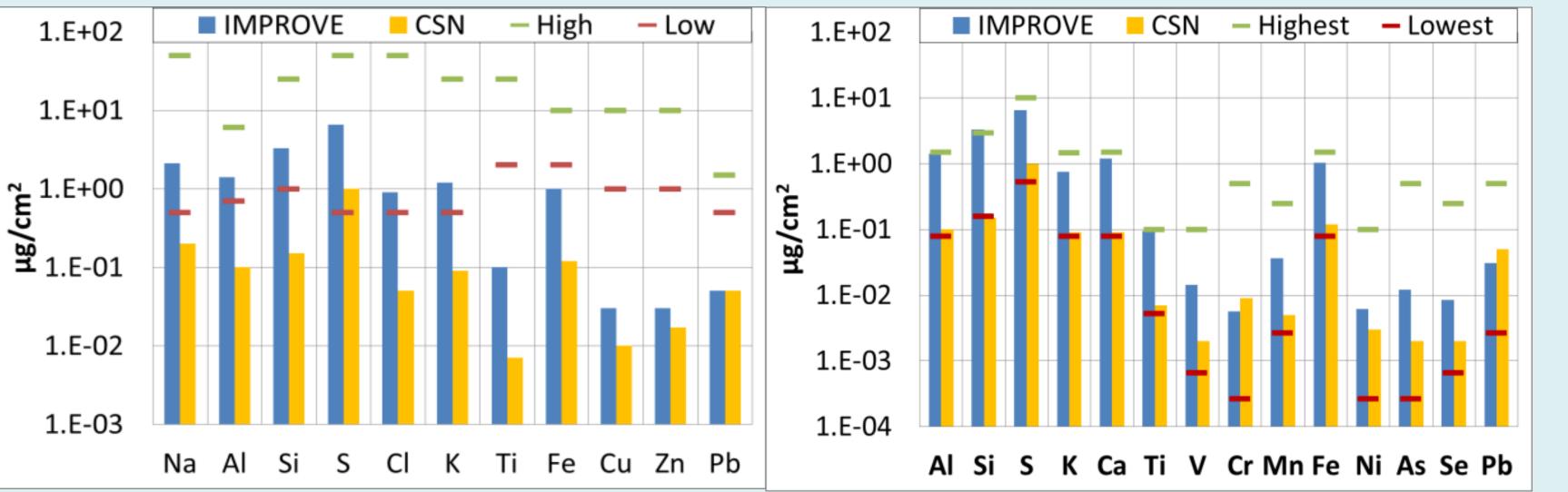
2. The potassium (K) measurement by UCD-EDXRF, C_{K.UCD-EDXRF}, (Epsilon 5, Panalytical Inc, the Netherlands) is accurate to be <10%. These assumptions resulted in estimated uncertainties below 10%.

Data Evaluation:

- Agreement between certified loadings of SE-RMs and EDXRF: Linear regression, bias and En number (ISO/IEC 17043, 2010):
- Linear regression between reference loading of ME-RMs (x) and lab (y),
- 3. z-score (ISO 13528:2005): Loadings in $\mu g/cm^2$ converted to $\mu g/g$ for 12 ME-RMs in interlaboratory comparison
 - C: outlier-excluded mean
 - $\hat{\sigma}$: outlier-excluded standard deviation

Results and Discussion

The SE-RMs could be generated successfully for Na, Al, Si, S, Cl, K, Ti, Fe, Zn and Pb with loadings almost spanning the range of two large US atmospheric PM monitoring networks, namely IMPROVE (Interagency Monitoring of PROtected Visual Environments) and CSN (Chemical Speciation Network) (Fig.2.-Left) while the loadings of ME-RMs spun the range of both networks (Fig.2-Right).



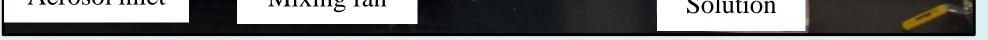
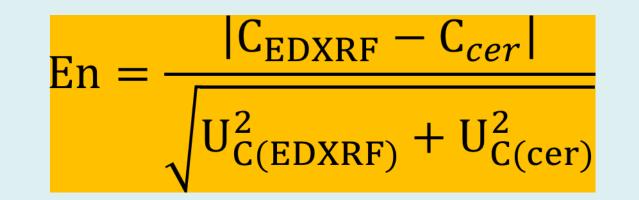


Fig.1. The aerosol generation and sampling system



For good interlaboratory comparability, $|z \le 3|$

Interlaboratory Comparison of ME-RMs

U:Expanded uncertainty by GUM (2008)

When $En \leq 1$, C_{FDXRF} and C_{cer} are equivalent

An interlaboratory comparison study of ME-RMs were conducted with participation of 9 XRF and 3 ICP-MS laboratories

- The slopes of reference vs. labs are mostly within 20% of unity $(R^2>0.95)$ (Fig.6)
- Participating labs are mostly in good agreement $(|z \le 3|)$ (Fig.7)

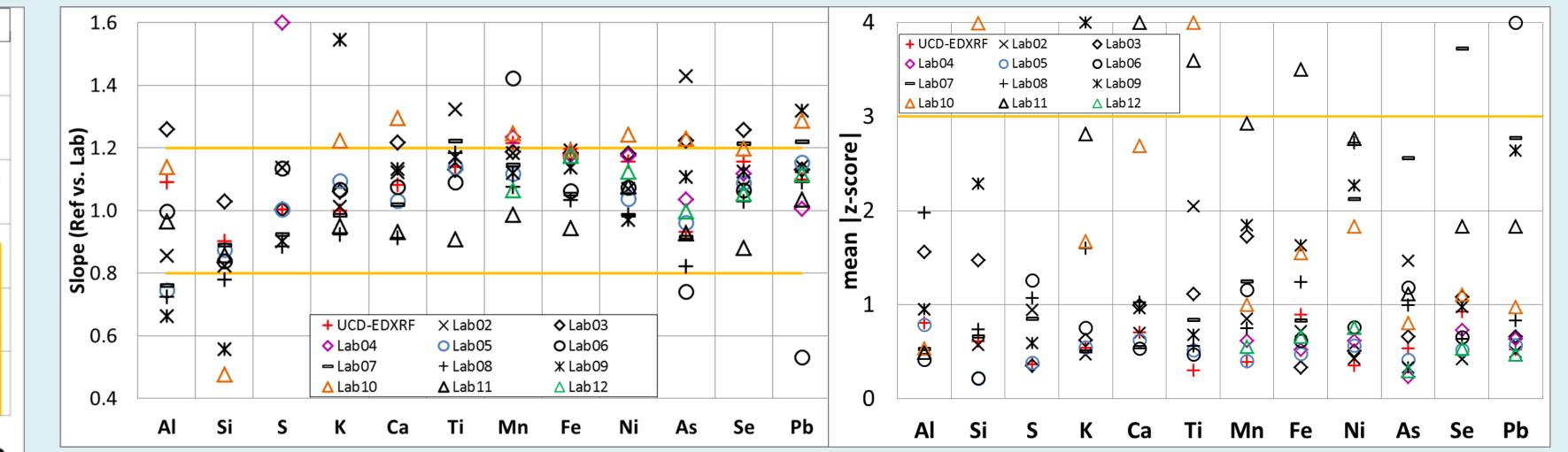


Fig.2. Left) The range of generated SE-RMs (Low and High); Right) ME-RMs (Lowest) and Highest) compare to IMPROVE and CSN 90%iles for selected elements.

- The slopes between C_{ref} and C_{EDXRF} (with intercept set to zero) are within 10% of unity. The EDXRF bias remained within 10% for Al, Si, S (at >1 μ g/cm²), Cl (with a few exceptions), K, Ti, Fe and Zn.
- \succ The En number remained <1 for most of the generated SE-RMs (Fig.3) Work in progress
- For Ca (CaTiO₃) and Cr (CrN) Issues to solve:
- Disagreement between certified (ratio) of Ca /Ti) vs. EDXRF (Fig.4) Ca enhancement effect?
- Disagreement between certified vs.

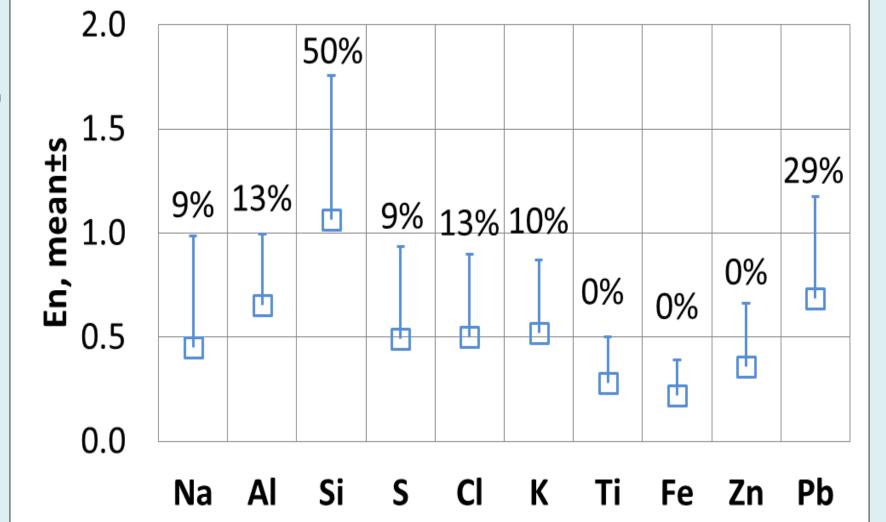
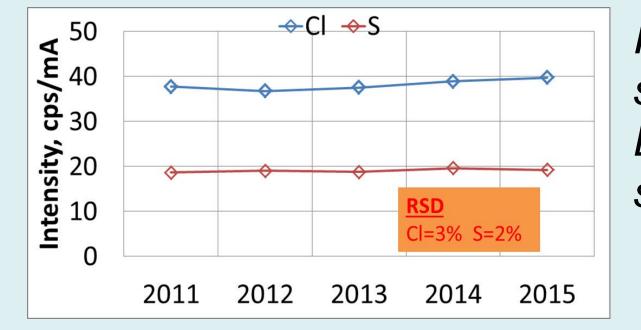


Fig.6. The slopes of reference versus labs for Fig.7. The absolute mean z-score of labs selected elements. Labs 10,11, and 12 are for selected elements. The mean z-score ICP-MS. The slopes higher than 1.6 were higher than 4 were shown at 4 for better shown at 1.6 for better resolution resolution

Selected SE-RMs were tested for short-term and long-term stability, and found to be to stable (Fig.8.)



 \succ Generated MEs also proved to be stable (Fig.9)

Fig.8. Long-term reproducibility of selected SE-RMs (2011-2015). Low RSD (<3%) show good stability of generated SE-RMs.

Fig.9. The relative standard deviation (RSD) of a ME-RM weekly analyzed by EDXRF since 2014 (n>200). Low RSD show

EDXRF for CrN (Fig.5) Influence of magnetic properties of CrN on gravimetric measurements?

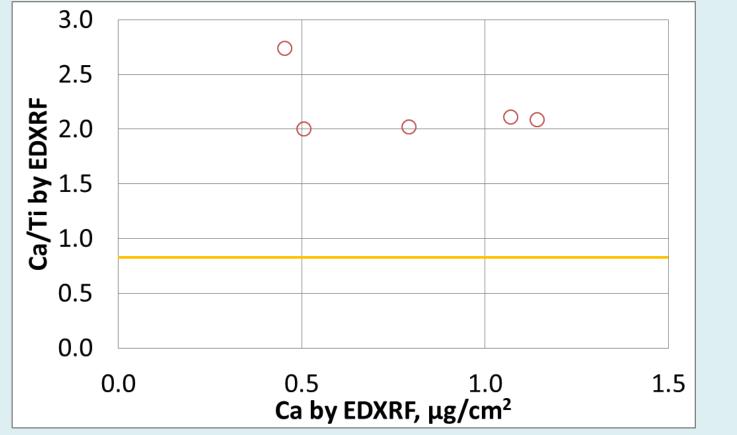
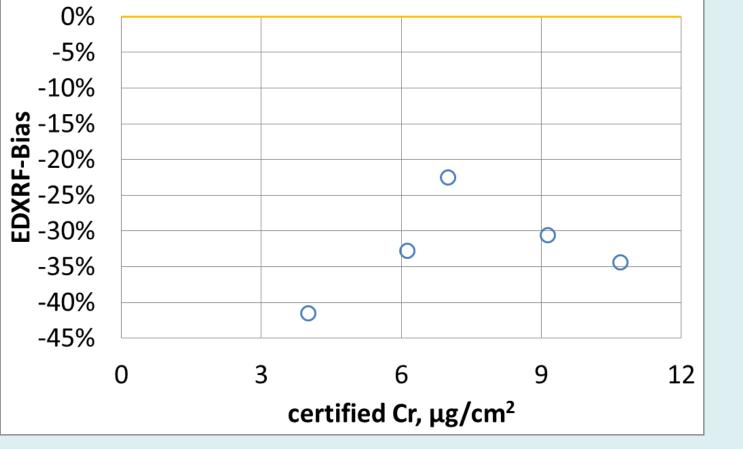


Fig.4. Ca/Ti ratio by EDXRF (points) vs. stoichiometric one (orange line)

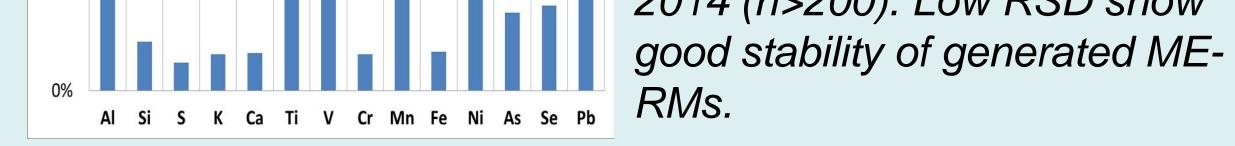
Acknowledgements:

This study was supported by the NPS under Contract C2350-06-4026 to the UCD. Thanks to participating laboratories and researchers: Margaret Cruz (UCD), Andrea McWilliams (RTI), Steven Kohl (DRI), Owen Butler (HSL-UK), Travis Ancelet (NIC-NZ), Marco van der Haar (Panalytical), Solomon Taffera (SC-AQMD) and Michel Gerboles (JRC, European Commission, Italy)

Fig.3. En number of EDXRF vs. certified loadings of SE-RMs. Numbers refer to percentages of En>1



EDXRF certified Cr bias from *Fig.5.* loadings generated from CrN



Conclusions

- Single-element (SE) certified reference material successfully generated on PTFE filters for Na, Al, Si, S, Cl, K, Ti, Fe, Zn and Pb
- * Multi-element (ME) reference materials mimicking ambient aerosols are successfully generated on PTFE filters
- For most of the elements, all laboratories participating in inter-laboratory comparison compare well with each other and with established reference loadings Checked SEs and ME-RMs show satisfactory stability except volatile elements SE-RMs can serve calibration/quality control materials for XRF systems
- The unique SEs and ME-RMs can serve as quality control samples, providing valuable information about performance of XRF systems typically calibrated with single compound/element standards

Publications

Indresand, H.; White, W. H.; Trzepla, K.; Perley, B. P.; Dillner, A.M., X-Ray Spectrom., 2012 Yatkin, S.; Amin, H.S.; Trzepla, K; Dillner, A.M., Aerosol Sci & Technol., 2016